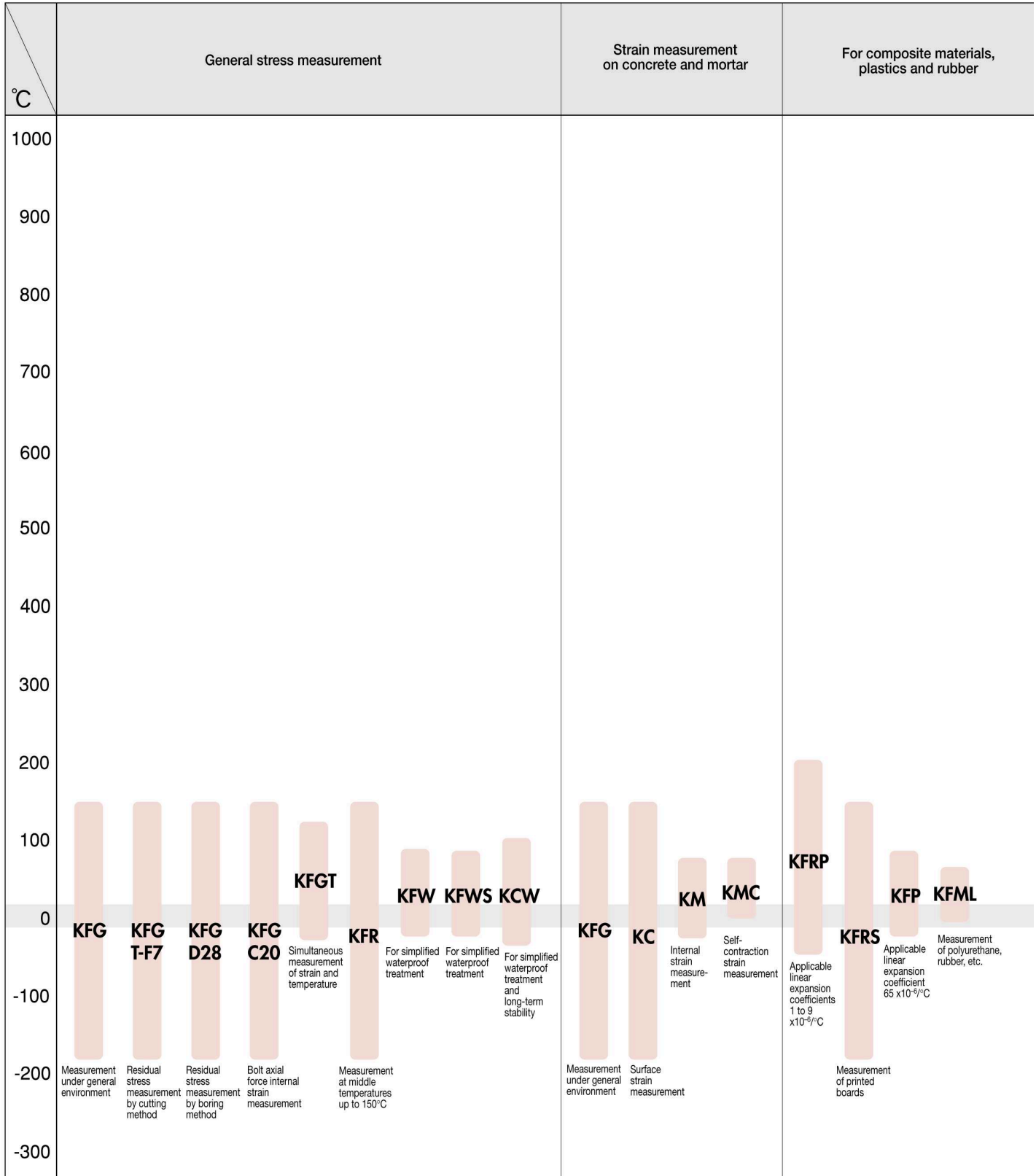


1a

Selecting a strain gage based on operating temperatures and other measuring conditions



Micro-strain measurement (semiconductor gages)	Measurement at high temperatures	Measurement at low temp.	Large strain measurement	For magneto-resistance	Measurement under other conditions	°F
	Measurement in a temperature range of -196 to 950°C KHCX					1832
	Measurement in a temperature range of room temperature to 800°C KHCD					1652
	Measurement in a temperature range of -196 to 750°C KHCS					1472
	Measurement in a temperature range of -196 to 650°C KHCM					1292
	Measurement in a temperature range of -196 to 550°C KHC					1112
	Measurement in a temperature range of -196 to 350°C KFU					932
	Measurement in a temperature range of -50 to 350°C KH					752
	Measurement in a temperature range of -196 to 250°C KFH					572
KSP KSN KSPL						392
KSPH						212
Measurement of less than 100µm/m strain under environment of less temperature change						32
Impact-initiated strain measurement with no amplifier						-148
		KFL	KLM Elongation measurement up to approx. 20%	KFEL Elongation measurement up to approx. 15%		-328
				KFN Measurement under AC magnetic field	KFS Measurement under high electric field generating inductive noise	-508
					KFF In the case where any gage cannot be bonded inside the structure	
					KCH Simplified waterproof treatment and ruggedness	
					KMP Internal strain measurement of resin	
					KTB Temperature measurement	
					KV Measurement of progress and propagation velocity of crack	

Note: Stated above are operating temperatures.